

Search Notes

Application/Control No.

10/711,633

Examiner

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Applicant(s)/Patent under
Reexamination

BAKIR ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	2	2/7/2006	JSL
716	8	2/7/2006	JSL
716	9	2/7/2006	JSL
716	10	2/7/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	2	2/7/2006	JSL
716	8	2/7/2006	JSL
716	9,10	2/7/2006	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	2/7/2006	JSL
IEEE	2/7/2006	JSL
GOOGLE	2/7/2006	JSL